

Application No.	Applicant(s)
10/019,020	FRISCH et al.
Examiner	Art Unit
Tu M. Nguyen	3748

	SEARCHED			
Class	Subclass	Date	Examiner	
60	274	5/2005	TMN	
	286			
	295			
	303			
123	531			
	533			
219	438			
	441			
222	145.5			
	145.6			
422	172			
	182	1	1	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

(INCLUDING SEAR	DATE	EXM
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